


<b>Search Notes</b>  	<b>Application/Control No.</b>  10596843	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA, HIDEO
	<b>Examiner</b>  LUCY P CHIEN	<b>Art Unit</b>  2871

SEARCHED			
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SEARCH NOTES		
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Please see attached search notes from EAST	1/12/2011	LC

INTERFERENCE SEARCH			
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349	51,40	1/12/2011	LC

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